

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not consider d. Include copy of this form with next communication to the applicant.

* Abstract provided for the Examiner's convenience

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PATENT AND TRADEMARK OFFICE

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

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APPLICANT
Kenya KOBAYASHI

FILING DATE 00
June 27, 2003

GROUP
2823

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
<i>ME</i>	AI	A 5055360	03/93	JP	—	—	with English abstract
<i>ME</i>	AJ	A 11-103033	04/99	JP	—	—	with English abstract
<i>ME</i>	AK	A 2002-26117	01/02	JP	—	—	with English abstract
<i>ME</i>	AL	A 4-3958	01/92	JP	—	—	with English abstract
	AO						
	AP						
	AQ						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

AT	
AU	
AV	
AX	
AY	

EXAMINER

Michelle Strada

DATE CONSIDERED

6/15/04

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